Electronic Supplementary Material (ESI) for Journal of Materials Chemistry
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Supplementary material for

Structural Defective Cerium Doped Lutetium-Yttrium Oxyorthosilicates for Optically Stimulated Luminescence Imaging Devices

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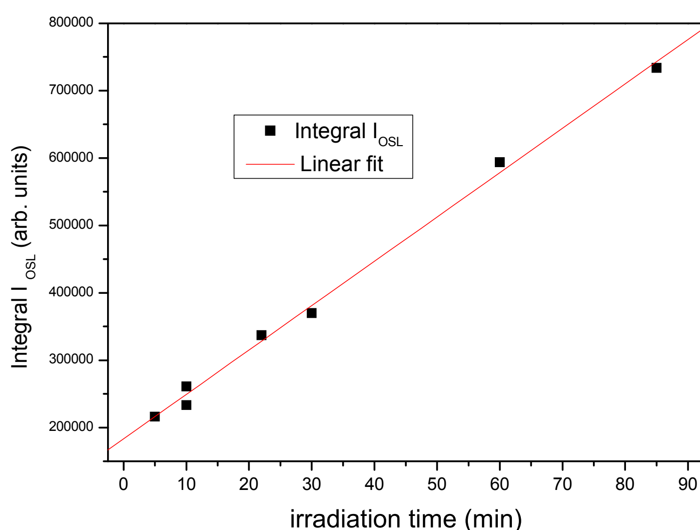
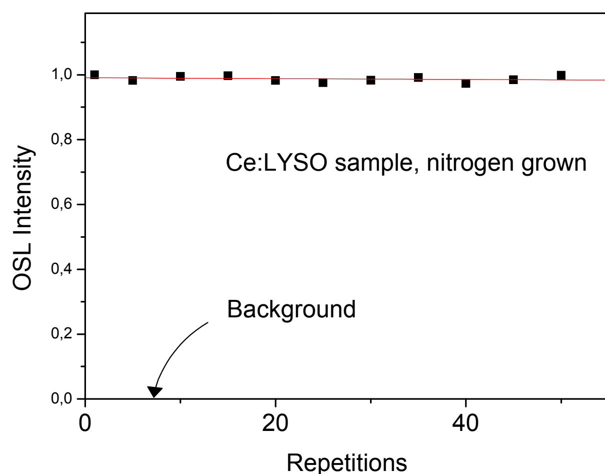
S1 - OSL Intensity as a function of the irradiation time with X-rays (20 kV, 20 mA). . The OSL was registered by exciting the sample with 514.5 nm line at 10 mw/cm^2.



S2 - OSL intensity values obtained after 15 s exposition to X-rays at 20 kV 20 mA. The OSL was registered by exciting the sample with 514.5 nm line at 10 mw/cm^2. The same procedure was repeated to test the reproducibility of the result (the values are normalized respect to the first measure for sake of clarity).



S3 - OSL intensity values obtained after long X-ray exposition (20 kV 20 mA). Each measure was obtained after heating treatment at 500 K for 10 minutes to empty the traps; then, the sample was irradiated for 15 s (X-rays 20 KV 20 mA) and the OSL was subsequently registered (514.5 nm -10 mW/cm^2). The